

# **FQAF34N25**

### 250V N-Channel MOSFET

#### **General Description**

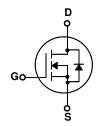
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters and switch mode power supplies.

#### **Features**

- 21.7A, 250V,  $R_{DS(on)}$  = 0.085 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 60 nC)
- Low Crss (typical 60 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





## **Absolute Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQAF34N25	Units
V <sub>DSS</sub>	Drain-Source Voltage		250	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	C)	21.7	Α
	- Continuous (T <sub>C</sub> = 100	°C)	13.7	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	86.8	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	700	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	21.7	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	10	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.8	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		100	W
	- Derate above 25°C		0.8	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.25	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	racteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		250			V
$\Delta BV_{DSS}$ / $\Delta T_J$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced t	to 25°C		0.27		V/°C
I <sub>DSS</sub>	Zana Oata Wallana Busin Oamani	V <sub>DS</sub> = 250 V, V <sub>GS</sub> = 0 V				10	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 200 V, T <sub>C</sub> = 125°C				100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10.9 A			0.067	0.085	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 10.9 A	(Note 4)		21		S
C <sub>iss</sub>	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			2110 465	2750 610	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance				60	80	pF
Switchi	ng Characteristics						
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 125 \text{ V}, I_{D} = 34 \text{ A},$ $R_{G} = 25 \Omega$			45	100	ns
t <sub>r</sub>	Turn-On Rise Time				335	680	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	116 - 20 22			110	230	ns
t <sub>f</sub>	Turn-Off Fall Time	(	Note 4, 5)		150	310	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 200 V, I <sub>D</sub> = 34 A,		-	60	80	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 10 \text{ V}$ (Note 4, 5)			14		nC
Q <sub>gd</sub>	Gate-Drain Charge				36		nC
Drain-S	Source Diode Characteristics ar	nd Maximum Ratings					
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current					21.7	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	Forward Current		1		86.8	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 21.7 \text{ A}$		ŀ		1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 34 \text{ A},$		-	220		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> / dt = 100 A/μs	(Note 4)		1.9		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.4mH, I<sub>AS</sub> = 21.7A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  34A, di/dt  $\leq$  300A/ $\mu$ s, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300 $\mu$ s, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

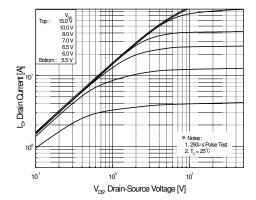


Figure 1. On-Region Characteristics.

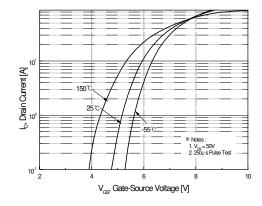


Figure 2. Transfer Characteristics.

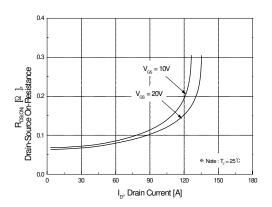


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage.

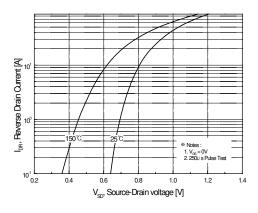


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature.

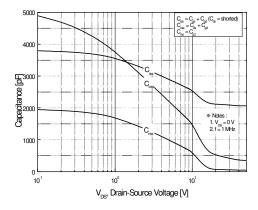


Figure 5. Capacitance Characteristics.

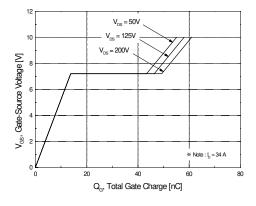
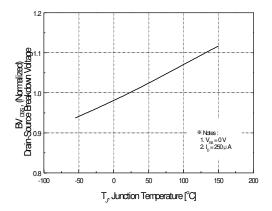


Figure 6. Gate -Charge Characteristics.

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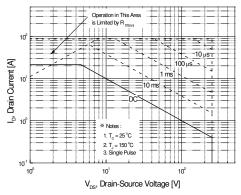
## Typical Characteristics (Continued)



(000 100 150 200 T<sub>y</sub> Junction Temperature [°C]

Figure 7. Breakdown Voltage Variation vs Temperature.

Figure 8. On-Resistance Variation vs Temperature.



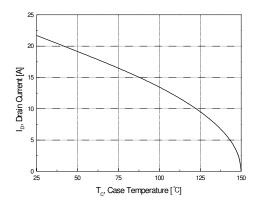


Figure 9. Maximum Safe Operating Area.

Figure 10. Maximum Drain Current vs Case Temperature.

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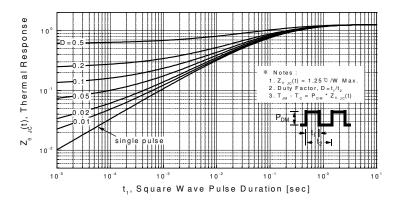
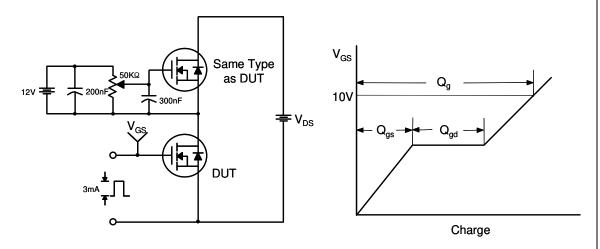


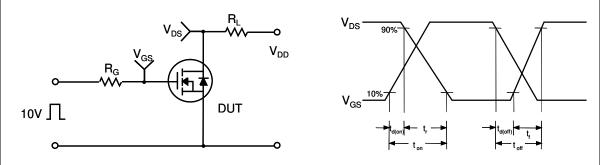
Figure 11. Transient Thermal Response Curve.

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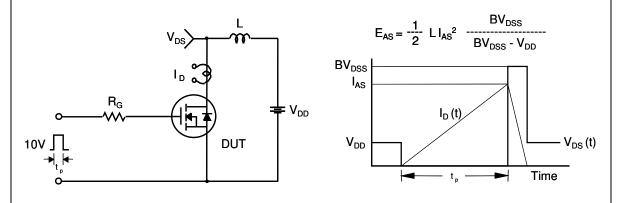
## **Gate Charge Test Circuit & Waveform**



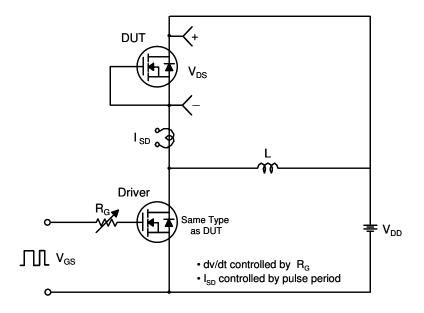
### **Resistive Switching Test Circuit & Waveforms**

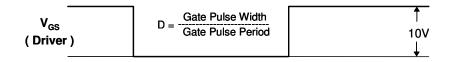


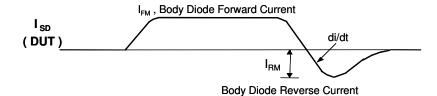
## **Unclamped Inductive Switching Test Circuit & Waveforms**

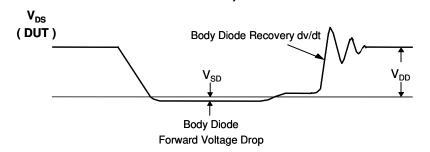


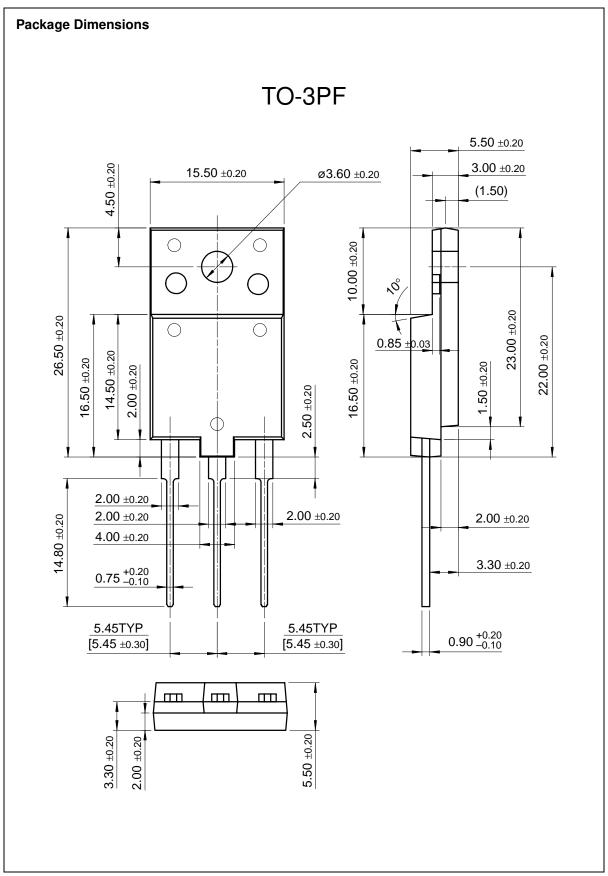
## Peak Diode Recovery dv/dt Test Circuit & Waveforms











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